

We claim:

1. A test contactor comprising:
conductive material defining at least one wall of a well to receive a device to be tested;

5 non-conductive material covering the conductive material; and
at least one electrical contact extending from the conductive material, to be electrically coupled to a ground plane.

2. The test contactor of claim 1, further comprising a base layer of non-conductive material supporting the conductive material.

3. The test contactor of claim 2, wherein the base layer defines a floor of the well.

4. The test contactor of claim 3, further comprising electrical connectors supported by the base layer, adjacent to the well, to electrically couple the device to be tested to test circuitry.

5. The test contactor of claim 4, wherein the electrical connectors are pins extending into the well.

6. The test contactor of claim 1, wherein the device to be tested has a first height and the wall of the well has a second height greater than the first height.

7. The test contactor of claim 6, wherein the second height is at least twice the height of the first height.

8. The test contactor of claim 7, wherein the conductive material is aluminum.

9. The test contactor of claim 8, wherein the non-conductive material is an anodized coating of the aluminum.

10. The test contactor of claim 9, wherein the anodized coating has a thickness of about 35 microns to about 50 microns.

11. The test contactor of claim 1, wherein the conductive material is aluminum.

12. The test contactor of claim 11, wherein the non-conductive material is an
5 anodized coating of aluminum.

13. The test contactor of claim 1, wherein the at least one wall defines at least one gap.

14. The test contactor of claim 1, wherein the conductive material defines a plurality of walls of the well and a gap between adjacent walls.

10 15. A test contactor comprising:
conductive material;
a first non-conductive material, wherein the conductive material is embedded in the non-conductive material and the embedded conductive material defines at least one wall of a well to receive a device to be tested;
15 a second conductive material supporting the embedded conductive material, wherein the second conductive material defines a floor of the well;
at least one electrical contact extending from the embedded conductive material, through the second conductive material, to be coupled to ground; and
electrical connectors supported by the second conductive material, adjacent to the
20 well, to electrically couple the device to be tested to test circuitry;
wherein the device to be tested has a first height and the conductive material of the wall has a second height greater than the first height.

16. The test contactor of claim 15, comprising a plurality of blocks of embedded conductive material, each block being separated from an adjacent block and each block defining a separate wall of the well, the blocks defining spaces between the walls and each block having a respective electrical contact extending therefrom to be coupled to ground.

17. The test contactor of claim 16, wherein the plurality of blocks are connected by embedded conductive material.

18. The test contactor of claim 17, wherein the second height is at least twice as large as the first height.

19. The test contactor of claim 18, wherein the conductive material is aluminum.

20. The test contactor of claim 19, wherein the first non-conductive material is an anodized coating of aluminum.

21. The test contactor of claim 18, wherein the second non-conductive material is a plastic.

22. The test contactor of claim 15, wherein the electrical contacts are pins extending into the well.

23. An assembly comprising:
 a test contactor comprising:
 conductive material defining at least one wall of a well to receive a device to be tested;
 non-conductive material covering the conductive material; and
 at least one grounding contact extending from the conductive material; and
 test circuitry comprising;

a ground plane, wherein the at least one grounding contact of the test contactor is electrically coupled to the ground plane;

wherein, when a device to be tested is received in the well, the device is electrically coupled to the test circuitry.

5 24. The assembly of claim 23, wherein the test circuitry comprises a test interface unit comprising the ground plane.

 25. The assembly of claim 24, wherein the test interface unit is a printed circuit board.

 26. The assembly of claim 25, wherein the printed circuit board further comprises at least one electrical contact to electrically couple each of the at least one grounding contacts to the ground plane.

 27. The assembly of claim 26, wherein the at least one electrical contact is a via.

 28. The assembly of claim 23, wherein the device to be tested has a first height and the wall has a second height at least twice the size of the first height.

 29. The assembly of claim 23, wherein the test contactor further comprises a base layer of a second conductive material supporting the conductive material.

 30. The assembly of claim 29, wherein the base layer defines a floor of the well and supports electrical connectors electrically connected to the test circuitry, to electrically couple the device to be tested to the test circuitry.

 31. The assembly of claim 30, further comprising a device to be tested, wherein:

 the device to be tested is received in the well; and

 the device to be tested comprises electrical contacts electrically coupled to the electrical connectors.